

STN	Súčasti pre nízkonapäťovú prepäťovú ochranu Časť 341: Výkonové požiadavky a skúšobné obvody na tyristorové prepäťové odrušovače (TSS)	STN EN IEC 61643-341 34 1395
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Components for low-voltage surge protection - Part 341: Performance requirements and test circuits for thyristor surge suppressors (TSS)

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 09/20

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NORME EUROPÉENNE

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July 2020

ICS 31.080.10

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amendments and corrigenda (if any)

English Version

**Components for low-voltage surge protection - Part 341:
Performance requirements and test circuits for thyristor surge
suppressors (TSS)
(IEC 61643-341:2020)**

Composants pour parafoudres basse tension - Partie 341:
Exigences de performance et circuits d'essai pour
parafoudres à thyristor (TSS)
(IEC 61643-341:2020)

Bauelemente für Überspannungsschutzgeräte für
Niederspannung - Teil 341: Leistungsanforderungen sowie
Prüfschaltungen für Suppressordioden (TSS)
(IEC 61643-341:2020)

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EN IEC 61643-341:2020 (E)**European foreword**

The text of document 37B/218/FDIS, future edition 2 of IEC 61643-341, prepared by SC 37B "Components for low-voltage surge protection" of IEC/TC 37 "Surge arresters" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61643-341:2020.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2021-03-17
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2023-06-17

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60060-1:2010	NOTE	Harmonized as EN 60060-1:2010 (not modified)
IEC 60068-2-20:2008	NOTE	Harmonized as EN 60068-2-20:2008 (not modified)
IEC 60068-2-21:2006	NOTE	Harmonized as EN 60068-2-21:2006 (not modified)
IEC 60099-4:2014	NOTE	Harmonized as EN 60099-4:2014 (not modified)
IEC 60721-3-3:2019	NOTE	Harmonized as EN IEC 60721-3-3:2019 (not modified)
IEC 60721-3-9:1993	NOTE	Harmonized as EN 60721-3-9:1993 (not modified)
IEC 60749-1:2002	NOTE	Harmonized as EN 60749-1:2003 (not modified)
IEC 60950-1:2005	NOTE	Harmonized as EN 60950-1:2006 (modified)
IEC 61000-4-5:2014	NOTE	Harmonized as EN 61000-4-5:2014 (not modified)
IEC 61643-11:2011	NOTE	Harmonized as EN 61643-11:2012 (modified)
IEC 62475:2010	NOTE	Harmonized as EN 62475:2010 (not modified)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

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NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-521	-	International Electrotechnical Vocabulary - Part 521: Semiconductor devices and integrated circuits	-	-
IEC 60068-2-20	2008	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	2008



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Edition 2.0 2020-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Components for low-voltage surge protection –
Part 341: Performance requirements and test circuits for thyristor surge
suppressors (TSS)**

**Composants pour parafoudres basse tension –
Partie 341: Exigences de performance et circuits d'essai pour parafoudres
à thyristor (TSS)**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMPONENTS FOR LOW-VOLTAGE SURGE PROTECTION –

Part 341: Performance requirements and test circuits for thyristor surge suppressors (TSS)

FOREWORD

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International Standard IEC 61643-341 has been prepared by subcommittee 37B, Components for low-voltage surge protection, of IEC technical committee 37: Surge arresters.

This second edition of IEC 61643-341 cancels and replaces the first edition published in 2001. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition: Addition of performance values.

The text of this standard is based on the following documents:

FDIS	Report on voting
37B/218/FDIS	37B/220/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 61643 series, under the general title *Components for low-voltage surge protective devices*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

COMPONENTS FOR LOW-VOLTAGE SURGE PROTECTION –

Part 341: Performance requirements and test circuits for thyristor surge suppressors (TSS)

1 Scope

This part of IEC 61643 specifies standard test circuits and methods for thyristor surge suppressor (TSS) components. These surge protective components, SPCs, are specially formulated thyristors designed to limit overvoltages and divert surge currents by clamping and switching actions. These SPCs are used in the construction of surge protective devices (SPDs) and equipment used in Information & Communications Technologies (ICT) networks with voltages up to AC 1 000 V and DC 1 500 V. This document is applicable to gated or non-gated TSS components with third quadrant (-v and -i) characteristics of blocking, conducting or switching.

This document contains information on

- terminology;
- letter symbols;
- essential ratings and characteristics;
- rating verification and characteristic measurement;

This document does not apply to the conventional three-terminal thyristors as covered by IEC 60747-6.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-521, *International Electrotechnical Vocabulary – Chapter 521: Semiconductor devices and integrated circuits*

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